A ONE-WEEK TRAINING IN ELECTROMAGNETIC COMPATIBILITY OF INTEGRATED CIRCUITS

COURSE DESCRIPTION

This course is designed for students, researchers, engineers who want to learn about EMC's topic.

The five-day course is focused on electromagnetic compatibility of integrated circuits.

A set of basic concepts is proposed as an introduction, covering specific units, parasitic impedance of interconnects, origin of noise, noise margins, time/frequency conversion and adaptations.

The 2nd focus concerns parasitic emission, how to design low emission circuits and how to measure the IC emission using standard IEC 61967 methods.

A $3^{\rm d}$ topic concerns susceptibility, with focus on measurement methods [IEC 62132] and hardware/software techniques to improve immunity to interference.

The 4th part is related to modeling approaches for predicting EMC (IEC 62433), based on standards such as IBIS, ICEM and ICIM.

The 5th part deals with EMC guidelines for improved emission and immunity to interference.

Finally, roadmaps and future challenges are briefly reviewed. Illustrations of these concepts are made using IC-EMC [www.ic-emc.org], a freeware including unique features and tools for efficient EMC simulations of integrated circuits.

Afternoons are dedicated to practical sessions including an access to the EMC laboratory of INSA Toulouse, for hands-on experiments of IC emission characterization (according to IEC 61967) and IC immunity characterization (IEC 62 132).

Lecturers

Etienne Sicard

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IEEE EMC Society Distinguished Lecturer

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18 to 22 September 2023

Duration

5 days - 30 hours

♦ Price: 2050€

1600€ for IEEE or SEE members 990 € for PhD Master Students

Documents & lunches included

Information & Registration:

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A certificate of attendance will be delivered at the end of the training

